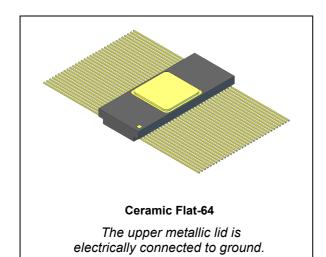


## RHFLVDS228A

## Rad-hard, dual 4x4 crosspoint switch LVDS

#### Datasheet - production data



#### **Features**

- LVDS input/output
- Multiple configuration: Mux, repeater and splitter
- ANSI TIA/EIA-644 compliant
- 400 Mbps LVDS (200 MHz)
- 200 MHz clock channel
- · Cold spare on all pins
- Fail-safe function
- 3.3 V operating power supply
- 4.8 V absolute rating
- Hermetic package
- Power consumption: 220 mW at 3.3 V

- Large input common mode: -4 V to +5 V
- Guaranteed up to 300 krad TID
- SEL immune up to 135 MeV.cm²/mg
- SET/SEU immune up to 22 MeV.cm²/mg

### Description

The RHFLVDS228A is an 8-channel, 4x4 crosspoint switch base, on low voltage differential signaling (LVDS) for low-power and high-speed communications. The two 4x4 multiplexers allow connection from any of the four inputs to any of the four outputs.

Packaged and qualified for use in aerospace environments in a low-power, fast-transmission standard, the RHFLVDS228A operates at 3.3 V power supply (3.6 V max. operating and 4.8 V AMR) and a common mode of -4 V to +5 V. The LVDS outputs operate over a controlled impedance of 100-ohm transmission media that may be printed circuit board traces, back planes, or cables.

The circuit features an internal fail-safe function to ensure a known state in case of an input short circuit or a floating input.

All pins have cold spare buffers to ensure they are in high impedance when  $V_{CC}$  is tied to GND. The RHFLVDS228A can operate over a wide temperature range of -55 °C to +125 °C and it is housed in an hermetic Ceramic Flat-64 package.

Table 1. Device summary

Reference	SMD pin	Quality level	Package	Lead finish	Mass	EPPL <sup>(1)</sup>	Temp. range	
RHFLVDS228AK1	-	Engineering model	Ceramic Flat-64	Gold	_	-	-55 °C to 125 °C	
RHFLVDS228AK01V <sup>(2)</sup>	TBD	QML-V flight	riai-04			Target	125 0	

- 1. EPPL = ESA preferred part list
- 2. Not yet in full production

Contents RHFLVDS228A

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# 1 Functional description

Table 2. Mux truth table

SL1	SL2	SL3	SL4	OUT1	OUT2	OUT3	OUT4	Mode
0	0	0	0	IN1	IN1	IN3	IN3	Splitter
0	0	0	1	IN1	IN1	IN3	IN4	Splitter/repeater
0	0	1	0	IN1	IN1	IN1	IN1	Splitter
0	0	1	1	IN1	IN1	IN4	IN4	Splitter
0	1	0	0	IN1	IN2	IN3	IN3	Splitter/repeater
0	1	0	1	IN1	IN2	IN3	IN4	Repeater
0	1	1	0	IN1	IN2	IN4	IN3	Repeater/switch
0	1	1	1	IN1	IN2	IN4	IN4	Splitter/repeater
1	0	0	0	IN2	IN2	IN2	IN2	Splitter
1	0	0	1	IN2	IN1	IN3	IN4	Switch/repeater
1	0	1	0	IN2	IN1	IN4	IN3	Switch
1	0	1	1	IN3	IN3	IN3	IN3	Splitter
1	1	0	0	IN2	IN2	IN3	IN3	Splitter
1	1	0	1	IN2	IN2	IN3	IN4	Splitter/repeater
1	1	1	0	IN4	IN4	IN4	IN4	Splitter
1	1	1	1	IN2	IN2	IN4	IN4	Spiller

Note: 1 A floating SL pin is equivalent to a low logic level

2 Channels 5, 6, 7, and 8 behave like channels 1, 2, 3 and 4 respectively (see also Figure 1)

Table 3. Enable (EN) truth table

EN	Inputs	Outputs		
EN	(IN+) - (IN-)	OUT+	OUT-	
L	X	Z	Z	
	Vid ≥ 0.1 V	Н	L	
□ or floating	Vid ≤-0.1 V	L	Н	
H or floating (internal pull-up)	-0.1V < Vid < +0.1 V	Unknown		
	Full fail-safe open/short or terminated	Н	L	

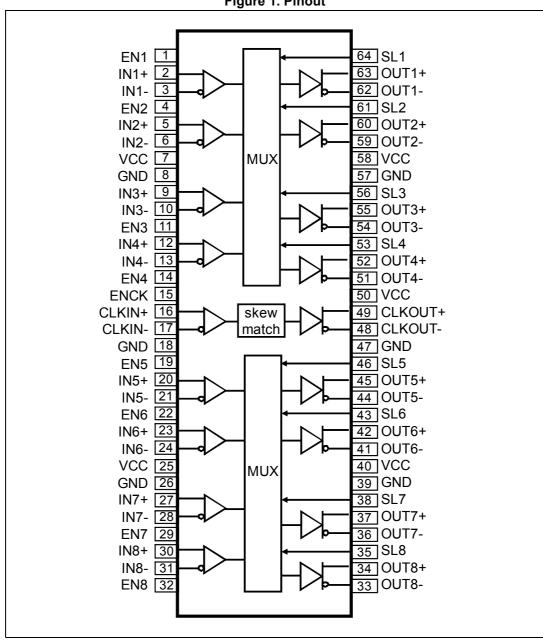
Note: Vid = (VIN+)-(VIN-), L = low level, H = high level, X = don't care, Z = high impedance



Pin configuration RHFLVDS228A

#### Pin configuration 2

Figure 1. Pinout



1. Power supplies are not internally separated. All Vcc pins must be connected to the same potential.

## 3 Maximum ratings and operating conditions

Absolute maximum ratings are those values beyond which damage to the device may occur. Functional operation under these conditions is not implied.

Table 4. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V <sub>CC</sub>	Supply voltage <sup>(1)</sup>	4.8	
V <sub>i</sub>	TTL inputs (operating or cold-spare)	-0.3 to 4.8	V
V <sub>CM</sub>	LVDS common mode (operating or cold-spare)	-5 to +6	
T <sub>stg</sub>	Storage temperature range	-65 to +150	°C
T <sub>j</sub>	Maximum junction temperature	+150	C
R <sub>thjc</sub>	Thermal resistance junction to case <sup>(2)</sup>	20	°C/W
ESD	HBM: Human body model  - All pins excepted LVDS inputs and outputs  - LVDS inputs and outputs vs. GND	2 8	kV
	CDM: Charge device model	500	V

<sup>1.</sup> All voltages, except the differential I/O bus voltage, are with respect to the network ground terminal.

**Table 5. Operating conditions** 

Symbol	Parameter	Min.	Тур.	Max.	Unit
V <sub>CC</sub>	Supply voltage	3	3.3	3.6	V
V <sub>CM</sub>	Static common mode	- 4		+ 5	V
T <sub>A</sub>	Ambient temperature range	-55		+125	°C



Short-circuits can cause excessive heating. Destructive dissipation can result from short-circuits on the amplifiers.

Electrical characteristics RHFLVDS228A

### 4 Electrical characteristics

### Total dose (MIL-STD-883 TM 1019)

The products guaranteed in radiation within the RHA QML-V system fully comply with the MIL-STD-883 TM 1019 specification.

The RHFLVDS228A is RHA QML-V, tested and characterized in full compliance with the MIL-STD-883 specification, between 50 and 300 rad/s only (full CMOS technology).

All parameters provided in *Table 7: Electrical characteristics table* apply to both pre- and post-irradiation, as follows:

- All test are performed in accordance with MIL-PRF-38535 and test method 1019 of MIL-STD-883 for total ionizing dose (TID).
- The initial characterization is performed in qualification only on both biased and unbiased parts.
- Each wafer lot is tested at high dose rate only, in the worst bias case condition, based on the results obtained during the initial qualification.

### **Heavy ions**

The behavior of the product when submitted to heavy ions is not tested in production. Heavy-ion trials are performed on qualification lots only.

Table 6. Radiations

Туре	Characteristics	Value	Unit
TID	High-dose rate (50 - 300 rad/sec)	300	krad
	SEL immunity up to: (with a particle angle of 60 °, at 125 °C)	135	
Heavy ions	SEL immunity up to: (with a particle angle of 0 °, at 125 °C)	67	MeV.cm²/mg
	SET/SEU immunity up to: (at 25 °C)	22	

In *Table 7* below,  $V_{CC}$  = 3 V to 3.6 V, capa-load (CL) = 10 pF, typical values are at  $T_{amb}$  = +25 °C, min. and max values are at  $T_{amb}$  = -55 °C and + 125 °C unless otherwise specified.

Table 7. Electrical characteristics table

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit	
Whole ci	rcuit						
I <sub>CCL</sub>	Total enabled supply current, drivers and receivers enabled, not switching	V <sub>ID</sub> = 400 mV and load = 100 Ω on all channels		67	80	m Λ	
I <sub>CCZ</sub>	Total disabled supply current, loaded or not loaded, drivers and receivers disabled	V <sub>ID</sub> = 400 mV EN and ENCK = GND			20	mA 20	
Digital in	puts EN, ENCK, and SL		- 1		•		
V <sub>IH</sub>	Input voltage high		2		V <sub>CC</sub>	V	
V <sub>IL</sub>	Input voltage low		GND		0.8	V	
I <sub>IH</sub>	High level input current	$V_{CC} = 3.6 \text{ V}, V_{IN} = V_{CC}$	-10		10		
I <sub>IL</sub>	Low level input current	V <sub>CC</sub> = 3.6 V, V <sub>IN</sub> = 0	-10		10	uА	
I <sub>OFF</sub>	TTL inputs power off leakage current	V <sub>CC</sub> = 0 V, EN and SL = 3.6 V	-10		10	μΑ	
LVDS inp	uts						
V	V <sub>TL</sub> Differential input low threshold	V <sub>CM</sub> = 1.2 V			-100	mV	
۷TL		-4 V < V <sub>CM</sub> < +5 V			-130		
\/	Differential input high threshold	V <sub>CM</sub> = 1.2 V	+100			IIIV	
$V_{TH}$	Differential input high threshold	-4V < V <sub>CM</sub> < +5 V	+130				
$V_{CMR}$	Common mode voltage range	V <sub>ID</sub> = 200 mVp-p	- 4		+5	V	
$V_{CMREJ}$	Common mode rejection <sup>(1)</sup>	F = 10 MHz			300	mVp-p	
I <sub>ID</sub>	Differential input current	V <sub>ID</sub> = 400 mVp-p	-10		10		
I <sub>ICM</sub>	Common mode input current	V <sub>IC</sub> = - 4 V to + 5 V	-70		70	μA	
I <sub>OFFIN</sub>	LVDS input power-off leakage current <sup>(2)</sup>	V <sub>CC</sub> = 0 V, V <sub>IN</sub> = -4 V to 5 V	-60		60	'	
C <sub>IN</sub>	Input capacitance			3		pF	
LVDS out	puts						
V <sub>OH</sub>	Output voltage high				1.65	V	
V <sub>OL</sub>	Output voltage low		0.925			V	
V <sub>OD</sub>	Differential output voltage		250		400		
DV <sub>OD</sub>	Change of magnitude of V <sub>OD</sub> for complementary output states				10	mV	
V <sub>OS</sub>	Offset voltage		1.125		1.45	V	
DV <sub>OS</sub>	Change of magnitude of V <sub>OS</sub> for complementary output states				25	mV	



Electrical characteristics RHFLVDS228A

Table 7. Electrical characteristics table (continued)

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I <sub>OS</sub>	Output short-circuit current	$V_{ID}$ = -400 mV and $V_{OUT}$ = 0 V $V_{ID}$ = +400 mV and $V_{OUT}$ = 0 V	-9			mA
I <sub>OZ</sub>	High impedance output current	Disabled, V <sub>OUT</sub> = 3.6 V or 0V	-10		10	
I <sub>OFFOUT</sub>	LVDS outputs power-off leakage current	V <sub>CC</sub> = 0 V, V <sub>OUT</sub> = 3.6 V	-50		+50	μΑ
T <sub>S</sub>	Input to SL setup time <sup>(3)</sup>		1.6			
T <sub>H</sub>	Input to SL Hold time <sup>(3)</sup>	Refer to Figure 4	1.5			
T <sub>Sw</sub>	SL to Switched output <sup>(3)</sup>				5	
t <sub>PHLD</sub>	Propagation delay time, high to low	V <sub>ID</sub> = 200 mVp-p, input pulse from 1.1 V to 1.3 V, V <sub>CM</sub> =1.2 V	1.5		4	
t <sub>PLHD</sub>	Propagation delay time, low to high	Load: refer to <i>Figure 2</i>	1.5		4	
t <sub>SK1</sub>	Channel to channel skew <sup>(3)(4)</sup>				0.5	
t <sub>SK2</sub>	Chip to chip skew <sup>(3)(5)</sup>	V <sub>ID</sub> = 200 mVp-p			0.7	
t <sub>SKD</sub>	Differential skew <sup>(6)</sup> (t <sub>PHLD</sub> -t <sub>PLHD</sub> )	Load: refer to <i>Figure 5</i>			0.5	ns
t <sub>r</sub>	Output signal rise time	Refer to Figure 3		0.9		
t <sub>f</sub>	Output signal fall time	Relei to Figure 3		0.9		
t <sub>PLZ</sub>	Propagation delay time, low level to high impedance output				2.8	
t <sub>PHZ</sub>	Propagation delay time, high level to high impedance output	Defer to Figure 5			2.8	
t <sub>PZH</sub>	Propagation delay time, high impedance to high level output	Refer to <i>Figure 5</i>			2.5	
t <sub>PZL</sub>	Propagation delay time, high impedance to low level output				2.5	
Fail-safe	and cold-spare	ı	1	1		
t <sub>D1</sub>	Fail-safe to active time			1		
t <sub>D2</sub>	Active to fail-safe time			1		μs
	1	1				

<sup>1.</sup> Guaranteed by characterization on bench.

<sup>2.</sup> All pins are floating except pin under test and V<sub>CC</sub>.

<sup>3.</sup> Guaranteed by design.

<sup>4.</sup>  $t_{SK1}$  is the maximum delay time difference between drivers on the same device (with all inputs connected together).

<sup>5.</sup> t<sub>SK2</sub> is the maximum delay time difference between outputs of all devices when they operate with the same supply voltage, at the same temperature.

<sup>6.</sup>  $t_{SKD}$  is the maximum delay time difference between  $t_{PHLD}$  and  $t_{PLHD}$  (see *Figure 3*).

### **Cold sparing**

The RHFLVDS228A features a cold spare input and output buffer. In high reliability applications, cold sparing enables a redundant device to be tied to the data bus with its power supply at 0 V ( $V_{CC}$  = GND) without affecting the bus signals or injecting current from the I/Os to the power supplies. Cold sparing also allows redundant devices to be kept powered off so that they can be switched on only when required. This has no impact on the application. Cold sparing is achieved by implementing a high impedance between the I/Os and  $V_{CC}$ . ESD protection is ensured through a non-conventional dedicated structure.

#### Fail-safe

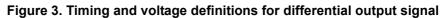
In many applications, inputs need a fail-safe function to avoid an uncertain output state when the inputs are not connected properly. In case of an LVDS input short circuit or floating inputs, the LVDS outputs remain in stable logic-high state.



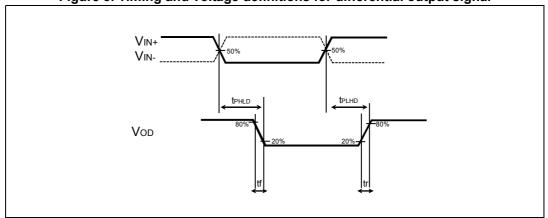
Test circuit RHFLVDS228A

## 5 Test circuit

Figure 2. Voltage and current definition



 $\frac{\Delta}{\Gamma}$ 



- 1. All input pulses are supplied by a generator with the following characteristics:  $t_r$  or  $t_f \le 1$  ns,  $t_f = 1$  MHz,  $t_f = 1$  MHz,  $t_f = 1$  ms,  $t_f$
- 2. The product is guaranteed with  $C_L$  = 10 pF.

RHFLVDS228A **Test circuit** 

Figure 4. MUX switch timings

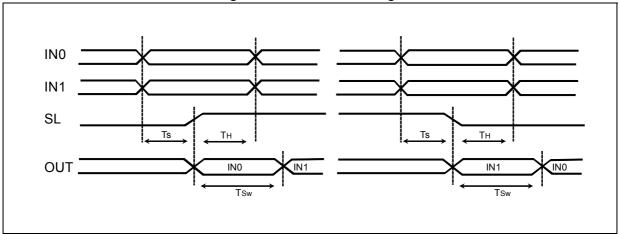
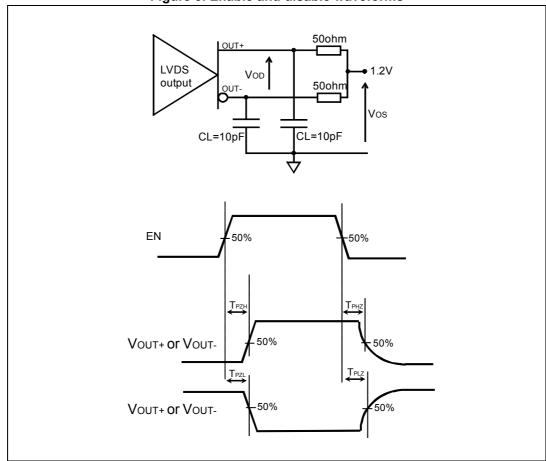


Figure 5. Enable and disable waveforms

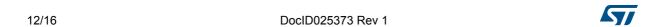


1. All input pulses are supplied by a generator with the following characteristics on EN:  $t_f$  or  $t_f \leq 1$  ns, F = 500 kHz, pulse width = 500 ns.

Package information RHFLVDS228A

# 6 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK<sup>®</sup> packages, depending on their level of environmental compliance. ECOPACK<sup>®</sup> specifications, grade definitions and product status are available at: <a href="https://www.st.com">www.st.com</a>. ECOPACK<sup>®</sup> is an ST trademark.



## 6.1 Ceramic Flat-64 package information

Figure 6. Ceramic Flat 64 package mechanical drawing

1. The upper metallic lid is electrically connected to ground.

Table 8. Ceramic Flat 64 package mechanical data

			Dimer	nsions		
Ref.		Millimeters			Inches	
	Min.	Тур.	Max.	Min.	Тур.	Max.
Α	2.41	2.66	2.92	0.095	0.105	0.115
A1	0.33	-	-	0.013	-	-
b	0.18	0.2	0.23	0.007	0.008	0.009
С	0.15	0.2	0.25	0.006	0.008	0.010
D	20.91	21.11	21.31	0.823	0.831	0.839
Е	8.64	8.76	8.89	0.340	0.345	0.350
E2	6.57	6.72	6.87	0.259	0.265	0.270
E3	-	1.02	-	-	0.040	-
е	-	0.635	-	-	0.025	-
L	12.45	12.7	12.95	0.49	0.5	0.51
S1	-	0.61	-	-	0.024	-

Ordering information RHFLVDS228A

#### **Ordering information** 7

Table 9. Order codes

Order code	Description	Temp. range	Package	Marking <sup>(1)</sup>	Packing	
RHFLVDS228AK1	Engineering model	-55 °C to	Ceramic Flat-64	RHFLVDS228AK1	Strip pack	
RHFLVDS228AK01V <sup>(2)</sup>	QML-V flight	123 0	1 181-04	TBD	pack	

- Specific marking only. Complete marking includes the following:
   SMD pin (on QML-V flight only)
   ST logo
   Date code (date the package was sealed) in YYWWA (year, week, and lot index of week)

  - QML logo (Q or V)Country of origin (FR = France).
- 2. Not yet in full production

Note:

Contact your ST sales office for information regarding the specific conditions for products in die form and QML-Q versions.

#### **Shipping information** 8

#### **Date code**

The date code is structured as follows:

Engineering model: EM xyywwz

QML flight model: FM yywwz

### Where:

x = 3 (EM only), assembly location Rennes (France)

yy = last two digits of the year

ww = week digits

z = lot index of the week

RHFLVDS228A Revision history

# 9 Revision history

Table 10. Document revision history

Date	Revision	Changes
29-Oct-2013	1	Initial release

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